


<b>Search Notes</b>  	<b>Application/Control No.</b>  10689091	<b>Applicant(s)/Patent Under Reexamination</b>  CHANG, YUAN-CHI
	<b>Examiner</b>  LEON HARPER	<b>Art Unit</b>  2166

SEARCHED			
Class	Subclass	Date	Examiner
707	104.1, 100, 10, 3	3/23/10	LJH

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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